

STD30NF06L

N-CHANNEL 60V - 0.022Ω - 35A DPAK/IPAK STripFET™ POWER MOSFET

TYPE	V _{DSS}	R _{DS(on)}	I _D
STD30NF06L	60 V	<0.028Ω	35 A

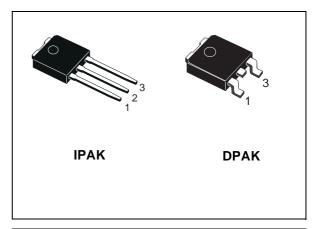
- TYPICAL $R_{DS}(on) = 0.022\Omega$
- EXCEPTIONAL dv/dt CAPABILITY
- LOGIC LEVEL GATE DRIVE
- ADD SUFFIX "T4" FOR ORDERING IN TAPE & REEL
- ADD SUFFIX "-1" FOR ORDERING IN IPAK
- CHARACTERIZATION ORIENTED FOR AUTOMOTIVE APPLICATIONS

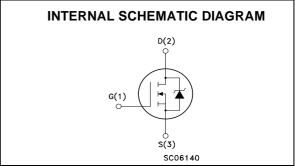
DESCRIPTION

This Power Mosfet is the latest development of STMicroelectronics unique "Single Feature SizeTM" strip-based process. The resulting transistor shows extremely high packing density for low on-resistance, rugged avalance characteristics and less critical alignment steps therefore a remarkable manufacturing reproducibility.



- HIGH-EFFICIENCY DC-DC CONVERTERS
- MOTOR CONTROL, AUDIO AMPLIFIERS
- DC-DC & DC-AC CONVERTERS
- AUTOMOTIVE





ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit		
V _{DS}	Drain-source Voltage (V _{GS} = 0)	60	V		
V _{DGR}	Drain-gate Voltage (R _{GS} = 20 k Ω)	60	V		
V _{GS}	Gate- source Voltage	± 20	V		
I _D	Drain Current (continuous) at T _C = 25°C	35	А		
I _D	Drain Current (continuous) at T _C = 100°C	25	А		
I _{DM} (●)	Drain Current (pulsed)	140	А		
P _{TOT}	Total Dissipation at T _C = 25°C	70	W		
	Derating Factor	0.46	W/°C		
dv/dt (1)	Peak Diode Recovery voltage slope	25	V/ns		
T _{stg}	Storage Temperature	FF to 17F			
Tj	Operating Junction Temperature	- 55 to 175			

(•) Pulse width limited by safe operating area July 2002

(1) I_{SD} \leq 38A, di/dt \leq 400A/ μ s, V_{DD} \leq V(BR)DSS, T $_{j}$ \leq T_{JMAX}.

1/10

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THERMAL DATA

Rthj-case	Thermal Resistance Junction-case Max	2.14	°C/W
Rthj-amb	Thermal Resistance Junction-ambient Max	100	°C/W
T _I	Maximum Lead Temperature For Soldering Purpose	275	°C

AVALANCHE CHARACTERISTICS

Symbol	Parameter	Max Value	Unit
I _{AR}	Avalanche Current, Repetitive or Not-Repetitive (pulse width limited by T_j max)	35	A
E _{AS}	Single Pulse Avalanche Energy (starting $T_j = 25$ °C, $I_D = I_{AR}$, $V_{DD} = 50$ V)	150	mJ

ELECTRICAL CHARACTERISTICS (TCASE = 25 °C UNLESS OTHERWISE SPECIFIED) OFF

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source Breakdown Voltage	$I_D = 250 \ \mu A, \ V_{GS} = 0$	60			V
I _{DSS}	Zero Gate Voltage	V _{DS} = Max Rating			1	μA
	Drain Current (V _{GS} = 0)	V _{DS} = Max Rating, T _C = 125 °C			10	μΑ
I _{GSS}	Gate-body Leakage Current (V _{DS} = 0)	V _{GS} = ± 20 V			±100	nA

ON (1)

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1	1.7	2.5	V
R _{DS(on)}	Static Drain-source On	V _{GS} = 5 V, I _D = 18 A		0.025	0.03	Ω
	Resistance	$V_{GS} = 10 \text{ V}, I_D = 18 \text{ A}$		0.022	0.028	Ω

DYNAMIC

Symbol	Parameter	r Test Conditions Min. T		Тур.	Max.	Unit
g _{fs} (1)	Forward Transconductance	$V_{DS} > =15 \text{ V}, I_{D} =15 \text{ A}$		25		S
C _{iss}	Input Capacitance	$V_{DS} = 25 \text{ V, f} = 1 \text{ MHz, V}_{GS} = 0$		1600		pF
Coss	Output Capacitance			215		pF
C _{rss}	Reverse Transfer Capacitance			60		pF

ELECTRICAL CHARACTERISTICS (CONTINUED)

SWITCHING ON

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
t _{d(on)}	Turn-on Delay Time	V _{DD} = 30 V, I _D = 18 A		30		ns
t _r	Rise Time	$R_G = 4.7\Omega V_{GS} = 4.5 V$ (see test circuit, Figure 3)		105		ns
Q _g Q _{gs} Q _{gd}	Total Gate Charge Gate-Source Charge Gate-Drain Charge	$V_{DD} = 48 \text{ V}, I_{D} = 38 \text{ A}, V_{GS} = 5 \text{ V}$		23 7 10	31	nC nC nC

SWITCHING OFF

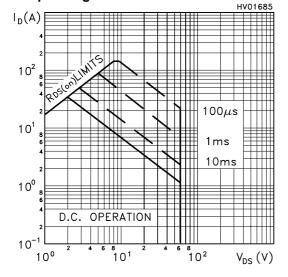
Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
t _{d(off)}	Turn-off-Delay Time Fall Time	$V_{DD} = 30 \text{ V}, I_{D} = 18 \text{ A},$ $R_{G} = 4.7\Omega, V_{GS} = 4.5 \text{ V}$		65 25		ns ns
		(see test circuit, Figure 3)				

SOURCE DRAIN DIODE

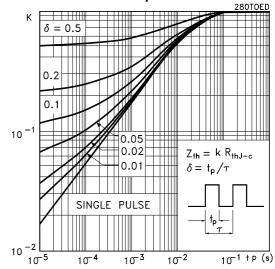
Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
I _{SD}	Source-drain Current				35	Α
I _{SDM} (2)	Source-drain Current (pulsed)	rrent (pulsed)				
V _{SD} (1)	Forward On Voltage	$I_{SD} = 35 \text{ A}, V_{GS} = 0$			1.5	V
t _{rr} Q _{rr} I _{RRM}	Reverse Recovery Time Reverse Recovery Charge Reverse Recovery Current	$I_{SD} = 38$ A, di/dt = 100 A/ μ s, $V_{DD} = 15$ V, $T_j = 150$ °C (see test circuit, Figure 5)		70 140 4		ns nC A

Note: 1. Pulsed: Pulse duration = 300 μs, duty cycle 1.5 %.
2. Pulse width limited by safe operating area.

Safe Operating Area

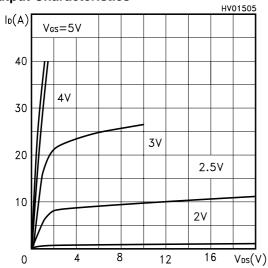


Normalized Thermal Impedence

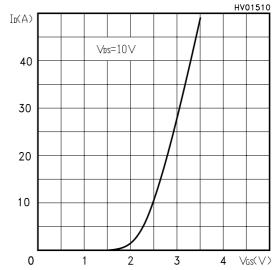


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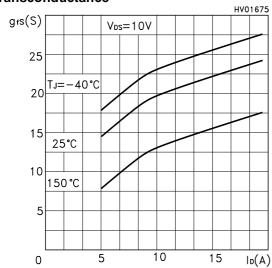
Output Characteristics



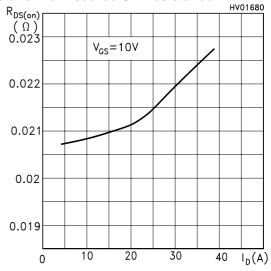
Transfer Characteristics

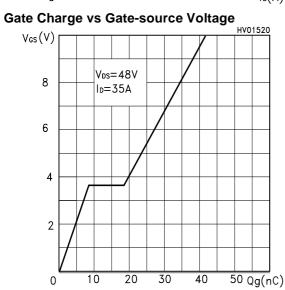


Transconductance

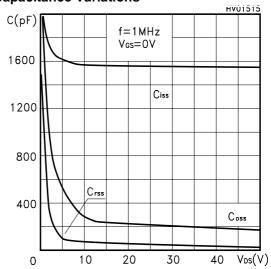


Static Drain-source On Resistance





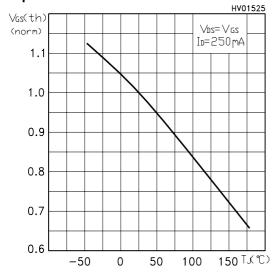
Capacitance Variations



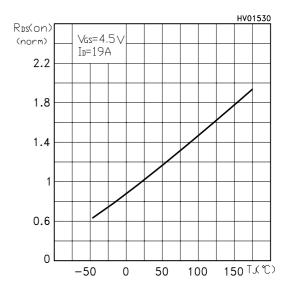
47/. 4/10

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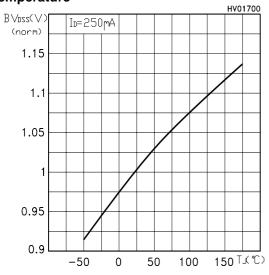
Normalized Gate Threshold Voltage vs Temperature



Normalized On Resistance vs Temperature



Normalized Drain-Source Breakdown vs Temperature



Source-drain Diode Forward Characteristics

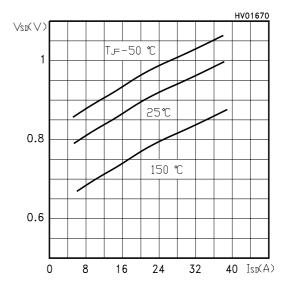


Fig. 1: Unclamped Inductive Load Test Circuit

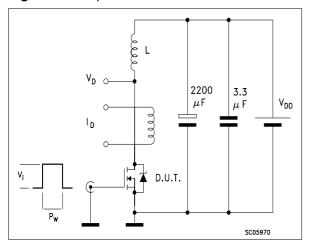


Fig. 3: Switching Times Test Circuit For Resistive Load

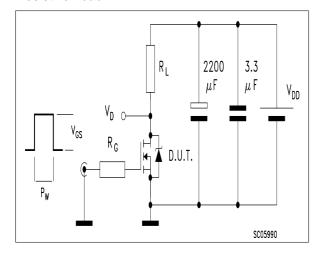


Fig. 5: Test Circuit For Inductive Load Switching And Diode Recovery Times

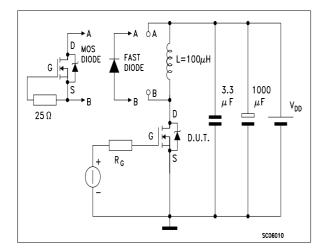


Fig. 2: Unclamped Inductive Waveform

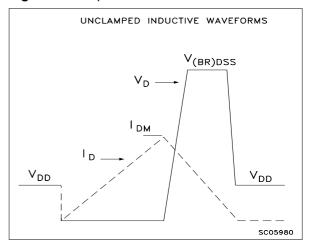
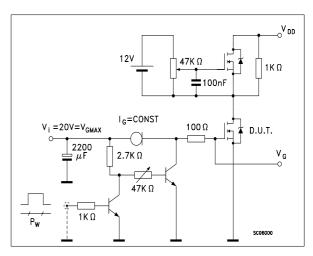


Fig. 4: Gate Charge test Circuit

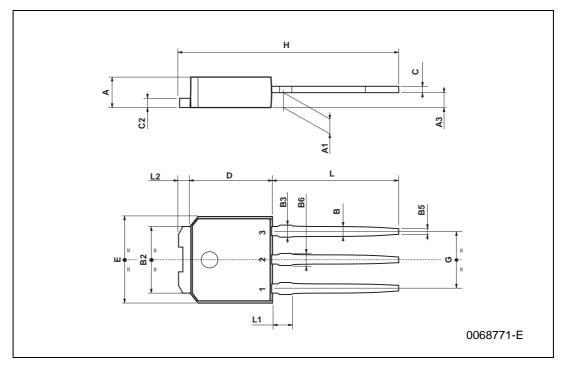


6/10

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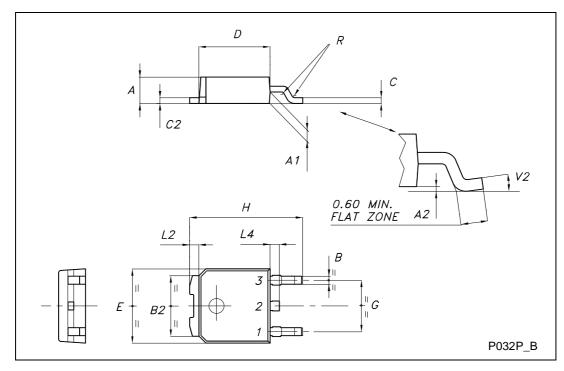
TO-251 (IPAK) MECHANICAL DATA

DIM.		mm			inch	
DIN.	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
А	2.2		2.4	0.086		0.094
A1	0.9		1.1	0.035		0.043
A3	0.7		1.3	0.027		0.051
В	0.64		0.9	0.025		0.031
B2	5.2		5.4	0.204		0.212
В3			0.85			0.033
B5		0.3			0.012	
B6			0.95			0.037
С	0.45		0.6	0.017		0.023
C2	0.48		0.6	0.019		0.023
D	6		6.2	0.236		0.244
Е	6.4		6.6	0.252		0.260
G	4.4		4.6	0.173		0.181
Н	15.9		16.3	0.626		0.641
L	9		9.4	0.354		0.370
L1	0.8		1.2	0.031		0.047
L2		0.8	1		0.031	0.039



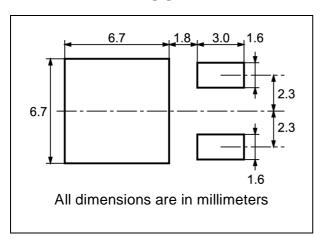
TO-252 (DPAK) MECHANICAL DATA

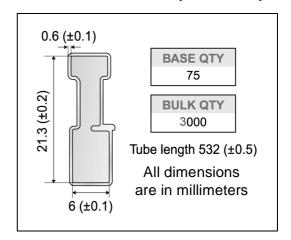
DIM.		mm			inch	
Dilvi.	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
А	2.20		2.40	0.087		0.094
A1	0.90		1.10	0.035		0.043
A2	0.03		0.23	0.001		0.009
В	0.64		0.90	0.025		0.035
B2	5.20		5.40	0.204		0.213
С	0.45		0.60	0.018		0.024
C2	0.48		0.60	0.019		0.024
D	6.00		6.20	0.236		0.244
Е	6.40		6.60	0.252		0.260
G	4.40		4.60	0.173		0.181
Н	9.35		10.10	0.368		0.398
L2		0.8			0.031	
L4	0.60		1.00	0.024		0.039
V2	0°		8°	0°		0°



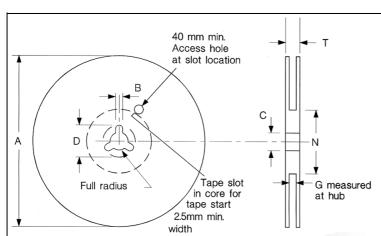
DPAK FOOTPRINT

TUBE SHIPMENT (no suffix)*





TAPE AND REEL SHIPMENT (suffix "T4")*

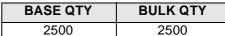


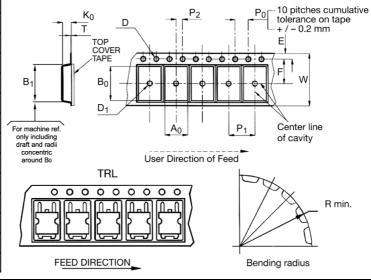
REEL MECHANICAL DATA

DIM.	mm		inch	
	MIN.	MAX.	MIN.	MAX.
Α		330		12.992
В	1.5		0.059	
С	12.8	13.2	0.504	0.520
D	20.2		0.795	
G	16.4	18.4	0.645	0.724
N	50		1.968	
Т		22.4		0.881

TAPE MECHANICAL DATA

DIM.	mm		inch	
	MIN.	MAX.	MIN.	MAX.
A0	6.8	7	0.267	0.275
В0	10.4	10.6	0.409	0.417
B1		12.1		0.476
D	1.5	1.6	0.059	0.063
D1	1.5		0.059	
Е	1.65	1.85	0.065	0.073
F	7.4	7.6	0.291	0.299
K0	2.55	2.75	0.100	0.108
P0	3.9	4.1	0.153	0.161
P1	7.9	8.1	0.311	0.319
P2	1.9	2.1	0.075	0.082
R	40		1.574	
W	15.7	16.3	0.618	0.641





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477. 10/10